

01-08-05  
AUG 04 2005  
JCT 178  
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*Ruth Montalvo*  
/ Ruth Montalvo Date: 08/04/05

Customer No. 026418

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Attorney's Docket No.: GK-ZEI-3269/500343.20289

U.S. Application No.: 10/533,603

International Application No.: PCT/EP2004/006302

International Filing Date: JUNE 11, 2004

11 JUNE 2004

Priority Date Claimed: JUNE 12, 2003

12 JUNE 2003

Title of Invention: METHOD FOR DETERMINING THE IMAGE QUALITY OF AN OPTICAL IMAGING SYSTEM

Applicant(s) for (DO/EO/US): Thomas ENGEL and Herbert GROSS

Mail Stop PCT  
Commissioner For Patents  
P.O. Box 1450  
Alexandria, VA 22313-450

## SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

S I R:

Supplemental to the information Disclosure Statement filed on April 29, 2005, applicants submits copies of the articles AX and AY previously omitted

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

**AX Literature: Joseph Geary, "Wavefront sensors", SPIE Press 1995;**  
**Chapters 3** (pgs 27-51), **4** (pgs 53-65), **5** (pgs 67-87), **6** (pgs 89-103),  
**8** (pgs 125-136) and **10** (pgs 151-167),

**AY Literature: Daniel Malacara, "Optical Shop Testing", Wiley Verlag 1992;**  
**Chapters 8** (pgs 265-314), **10** (pgs 367-396) and **11** (pgs 397-426),.

Accompanying this Supplemental Information Disclosure Statement and Supplemental form PTO-1449 are copies of the articles AX and AY, mentioned on page 3 of the substitute specification.

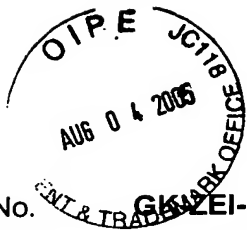
This submission is not an admission that the information disclosed in the documents is material to the patentability of the invention disclosed and/or claimed in the above-identified application.

Respectfully submitted,

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Enclosures:  
PTO-1449 & Articles;

**LIST OF PRIOR ART CITED BY APPLICANT**  
(SUPPLEMENTAL Filed on AUGUST 4, 2005)Docket No. **LEI-3269/500343.20289**Applicant(s): **Thomas ENGEL and Herbert GROSS**Application No. **10/533,603**

Group:

Filed: **April 29, 2005**

Examiner:

**U.S. PATENT DOCUMENTS**

Exam. Init		Document Number	Date	Name	Class	Sub-Class	Filing Date Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

**FOREIGN PATENT DOCUMENTS**

		Document Number	Date	Country	CLASS	Sub-Class	Translation	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							
	AQ							
	AR							
	AS							
	AT							

**OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)**

	AX	<b>Literature: Joseph Geary, "Wavefront sensors", SPIE Press 1995; Chapters 3 (pgs 27-51), 4 (pgs 53-65), 5 (pgs 67-87), 6 (pgs 89-103), 8 (pgs 125-136), and 10 (pgs 151-167),</b>
	AY	<b>Literature: Daniel Malacara, "Optical Shop Testing", Wiley Verlag 1992; Chapters 8 (pgs 265-314), 10 (pgs 367-396) and 11 (pgs 397-426),.</b>
	AZ	

Examiner:

Date:

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.